S	earch	Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/715,039	SUN ET AL.	
Examiner	Art Unit	•
Y. Lee	2621	

SEARCHED			
Class	Subclass	Date	Examiner
375	240.01 240.12 240.27 240.29	7/9/2007	YL
H04N	7/12		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
375	240.27	7/19/2007	YL
	240.29		
	•		

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
consulted with M. Dastouri w.r.t. 101	7/9/2007	YL